Abstracts

An SOLR calibration for accurate measurement of orthogonal on-wafer DUTs

S. Basu and L. Hayden. "An SOLR calibration for accurate measurement of orthogonal on-wafer DUTs." 1997 MTT-S International Microwave Symposium Digest 3. (1997 Vol. III [MWSYM]): 1335-1338.

Orthogonal CPW thrus are notorious for generating undesired modes due to the bend discontinuity. These undesired modes are not accounted for in conventional calibration methods such as SOLT, LRM, and TRL, since they require, by definition, well-behaved thru standards. In this paper, we will demonstrate through experimental results how the Short-Open-Load-Reciprocal thru (SOLR) approach, which avoids imposing any dependency on the nature of the thru standard itself, provides a superior calibration.

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